Se	Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/812,972	NIEN ET AL.	
Examiner	Art Unit	
Fric Chang	2116	

	SEARCHED		
Class	Subclass	Date	Examiner
713	320	11/22/2007	EC

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEAR (INCLUDING S	CH NOT EARCH S	ES STRATEGY)
		DATE	EXMR
EAST USPAT/PGPUB EPO/JPO		11/22/2007	EC
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